

Notice of References Cited	Application/Control No. 10/757,829	Applicant(s)/Patent Under Reexamination SHIRAISHI ET AL.	
	Examiner Tai Van Nguyen	Art Unit 3729	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,688,728	11-1997	Niwa et al.	501/80
	C	US-5,948,482	09-1999	Brinker et al.	516/33
	D	US-5,792,058	08-1998	Lee et al.	600/459
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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